TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7PA19AFE

Chip Select Decoder

Features

- Operating voltage range: V_{CC} = 1.4~3.6 V
- High-speed operation: t_{pd} = 3.3 ns (max) at V_{CC} = 3.0~3.6 V
 - t_{pd} = 3.9 ns (max) at V_{CC} = 2.3~2.7 V

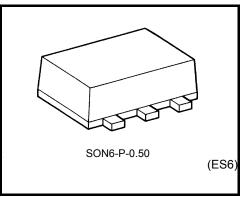
 t_{pd} = 8.0 ns (max) at V_{CC} = 1.65~1.95 V

 t_{pd} = 10.0 ns (max) at V_{CC} = 1.4~1.6 V

High-level output current:

 $I_{OH}/I_{OL} = \pm 24$ mA (min) at V_{CC} = 3.0 V $I_{OH}/I_{OL} = \pm 18$ mA (min) at V_{CC} = 2.3 V $I_{OH}/I_{OL} = \pm 4$ mA (min) at V_{CC} = 1.4 V

• 3.6 V tolerant inputs



Weight: 0.003 g (typ.)

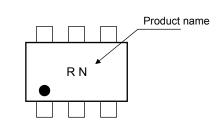
Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Value	Unit	
Power supply voltage	V _{CC}	-0.5~4.6	V	
DC input voltage	VIN	-0.5~4.6	V	
DC output voltage	Varia	-0.5~V _{CC} + 0.5	V	
DC output voltage	Vout	(Note 1)		
Input diode current	I _{IK}	-50	mA	
Output diode current	I _{OK}	±50 (Note 2)	mA	
DC output current	IOUT	+50	mA	
Power dissipation	PD	150	mW	
DC V _{CC} /ground current	ICC	±100	mA	
Storage temperature	T _{stg}	-65~150	°C	

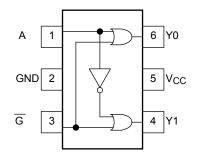
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 1: High or Low state. The I_{OUT} absolute maximum rating must be adhered to.
- Note 2: V_{OUT} < GND, V_{OUT} > V_{CC}

Marking



Pin Assignment (top view)



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Truth Table

Ing	Inputs		puts	
Enable	Select	Y0	Y1	Selected Output
G	А	τŪ	Ϋ́Ι	
Н	Х	Н	Н	None
L	L	L	Н	Y0
L	Н	Н	L	Y1

Operating Ranges

Characteristics	Symbol	Value	Unit
Power supply voltage	Vcc	1.4~3.6	V
Power supply voltage	vCC	1.2~3.6 (Note 3)	v
Input voltage	V _{IN}	-0.3~3.6	V
Output voltage	V _{OUT}	0~V _{CC} (Note 4)	V
		±24 (Note 5)	
Output Current	I _{OH} /I _{OL}	±18 (Note 6)	mA
		±4 (Note 7)	
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	dt/dv	0~10 (Note 8)	ns/V

Note 3: Data retention only

Note 4: High or Low state

Note 5: $V_{CC} = 3.0 \sim 3.6 \text{ V}$

Note 6: $V_{CC} = 2.3 \sim 2.7 \text{ V}$

Note 7: $V_{CC} = 1.4 \sim 1.9 \text{ V}$

Note 8: $V_{IN} = 0.8 \text{~} 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$

DC Electrical Characteristics (Ta = -40~85°C, 2.7 V < V_{CC} \leq 3.6 V)

Characteristics	Symbol	Tost	Test Condition			Max	Unit
Characteristics	Symbol	Test c	Sonation	V _{CC} (V)	Min	IVIAX	Offic
High-Level Input Voltage	V _{IH}		_	2.7~3.6	2.0	_	v
Low-Level Input Voltage	VIL			2.7~3.6	_	0.8	v
		IO	I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	_	V
High-Level Output Voltage	V _{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -12 mA	2.7	2.2	_	
			I _{OH} =18 mA	3.0	2.4	_	
			I _{OH} = -24 mA	3.0	2.2	_	
		$V_{IN} = V_{IH} \text{ or } V_{IL} \frac{I_{OL} = 100 \ \mu \text{A}}{I_{OL} = 12 \ \text{mA}}$ $I_{OL} = 18 \ \text{mA}}{I_{OL} = 24 \ \text{mA}}$	I _{OL} = 100 μA	2.7~3.6	_	0.2	
Low Lovel Output Valtage			I _{OL} = 12 mA	2.7	_	0.4	v
Low-Level Output Voltage	V _{OL}		I _{OL} = 18 mA	3.0	_	0.4	
			I _{OL} = 24 mA	3.0	_	0.55	
Input Leakage Current	I _{IN}	V _{IN} = 0~3.6 V		2.7~3.6	_	±10.0	μA
Quieseent Supply Current			$V_{IN} = V_{CC}$ or GND			20.0	
Quiescent Supply Current	ICC	$V_{CC} \leq V_{IN} \leq 3.6$	$V_{CC} \leq V_{IN} \leq 3.6 V$		_	±20.0	μA
Increase in I _{CC} per Input	Δlcc	$V_{IH} = V_{CC} - 0.6$ V	/	2.7~3.6	_	750	

DC Electrical Characteristics (Ta = -40~85°C, 2.3 V \leq V_{CC} \leq 2.7 V)

Characteristics	Symbol	Test (Test Condition			Max	Unit		
Characteristics	Cymbol				Min	IVIAA	Onit		
High-Level Input Voltage	VIH		—	2.3~2.7	1.6	—	v		
Low-Level Input Voltage	V _{IL}			2.3~2.7	_	0.7	v		
			I _{OH} = -100 μA	2.3~2.7	V _{CC} - 0.2	_			
High-Level Output Voltage	V _{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	VIN = VIH or VIL	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -6 mA	2.3	2.0	_	V
			I _{OH} = -12 mA	2.3	1.8	_			
			I _{OH} = -18 mA	2.3	1.7	_			
		$V_{IN} = V_{IH}$ or V_{IL}	I _{OL} = 100 μA	2.3~2.7	_	0.2	v		
Low-Level Output Voltage	V _{OL}		I _{OL} = 12 mA	2.3	_	0.4	v		
			I _{OL} = 18 mA	2.3	_	0.6			
Input Leakage Current	l _{IN}	V _{IN} = 0~3.6 V		2.3~2.7	_	±10.0	μA		
Quiescent Supply Current		V _{IN} = V _{CC} or GND		2.3~2.7	_	20.0			
	Icc	$V_{CC} \leq V_{IN} \leq 3.6$	$V_{CC} \leq V_{IN} \leq 3.6 V$			±20.0	μA		

DC Electrical Characteristics (Ta = $-40 \sim 85^{\circ}$ C, 1.4 V \leq V_{CC} < 2.3 V)

Characteristics	Symbol Test Condition				Min	Max	Unit
Characteristics	Symbol	Test Condition		V _{CC} (V)	IVIIII	Wax	Offic
High-Level Input Voltage	V _{IH}	—		1.4~2.3	$\begin{array}{c} V_{CC} \\ \times \ 0.7 \end{array}$		V
Low-Level Input Voltage	V _{IL}	—		1.4~2.3	_	V _{CC} × 0.13	v
High-Level Output Voltage	V _{OH}	V _{OH} V _{IN} = V _{IH} or V _{IL}	I _{OH} = -100 μA	1.4	V _{CC} - 0.2	_	V
			I _{OH} = -4 mA	1.4	1.0	_	
Low Lovel Output Veltage	Va	VIN = VIH or VIL	I _{OL} = 100 μA	1.4	_	0.2	v
Low-Level Output Voltage	V _{OL}	VIN = VIH OI VIL	I _{OL} = 4 mA	1.4	_	0.3	v
Input Leakage Current	I _{IN}	V _{IN} = 0~3.6 V		1.4	_	±10.0	μA
Quiescent Supply Current	ICC	V _{IN} = V _{CC} or GND		1.4		20.0	
Quiescent Supply Current		$V_{CC} \leq V_{IN} \leq 3.6 V$		1.4		±20.0	μA

AC Electrical Characteristics (Ta = $-40 \sim 85^{\circ}$ C, input t_r = t_f = 2.0 ns)

Characteristics	Symbol	Test Condition V _{CC} (V)		Min	Max	Unit	
				1.5 ± 0.1	1.8	10.0	
	C _L =15pF,	1.8 ± 0.15	1.5	8.0			
			$R_L = 1M\Omega$	2.5 ± 0.2	0.8	3.9	ns
Propagation delay time	tion delay time t _{pLH}	(Figure 1 and 2)	2)	$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.3	
(A or \overline{G} – Y0 or Y1) t _{pHL}	t _{pHL}			1.5 ± 0.1	2.0	13.0	
			C _L =30pF,	1.8 ± 0.15	1.8	9.5	ns
			R _L =500Ω	2.5 ± 0.2	1.2	5.0	115
				3.3 ± 0.3	1.0	4.0	

For C_L = 50 pF, add approximately 300 ps to the AC maximum specification.

Capacitive Characteristics (Ta = 25°C)

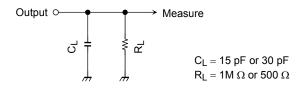
Characteristics	Symbol	Test Condition			TYP.	Unit
Characteristics	Symbol			V _{CC} (V)	IIF.	Unit
Input Capacitance	C _{IN}	—		1.8, 2.5, 3.3	6	pF
Power Dissipation Capacitance	C _{PD}	f _{IN} = 10 MHz	(Note 9)	1.8, 2.5, 3.3	20	pF

Note 9: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

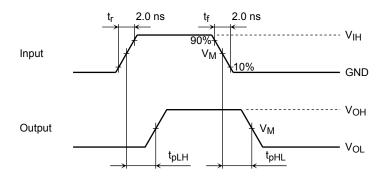
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Figure 1 Test Circuit



AC Waveforms

Figure 2 t_{pLH}, t_{pHL}



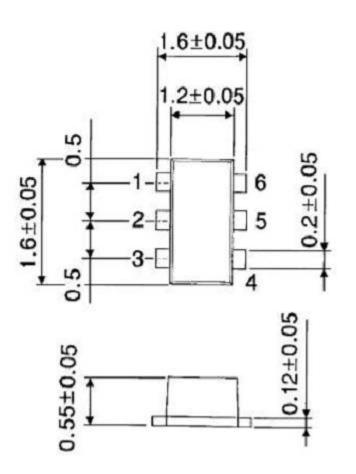
Symbol		V _C	V _{CC}			
Symbol	$3.3\pm0.3~V$	$2.5\pm0.2~V$	$1.8\pm0.15\;V$	$1.5\pm0.1\;V$		
VIH	2.7 V	V _{CC}	V _{CC}	V _{CC}		
VM	1.5 V	V _{CC} /2	V _{CC} /2	V _{CC} /2		

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Package Dimensions

SON6-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

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20070701-EN GENERAL

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